To all our customers

Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

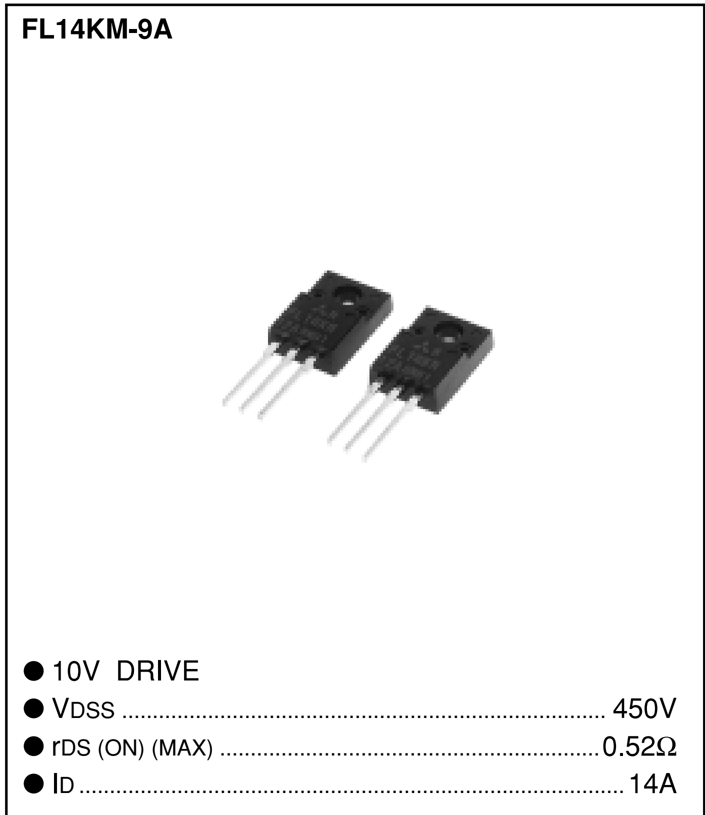
Note : Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp.
Customer Support Dept.
April 1, 2003

MITSUBISHI Nch POWER MOSFET

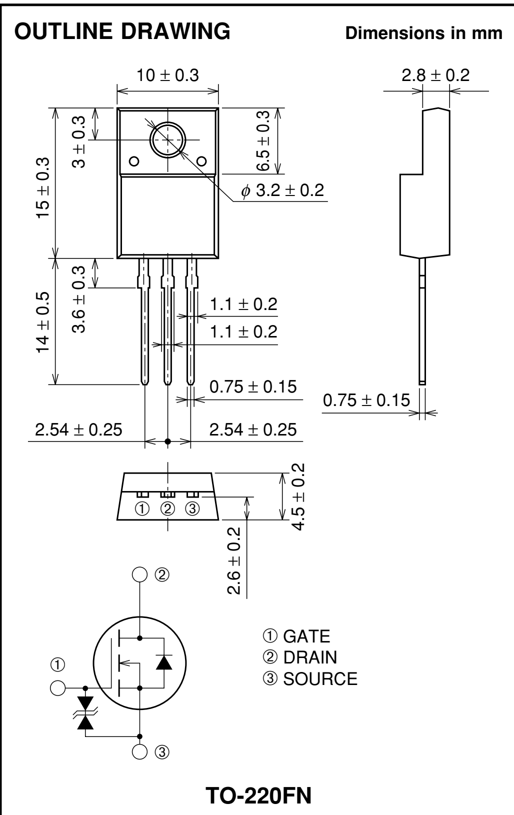
FL14KM-9A

HIGH-SPEED SWITCHING USE



FL14KM-9A

- 10V DRIVE
- V_{DSS} 450V
- r_{DS} (ON) (MAX) 0.52Ω
- I_D 14A



APPLICATION

SMPS, Inverter fluorescent light sets, etc.

MAXIMUM RATINGS (T_c = 25°C)

Symbol	Parameter	Conditions	Ratings	Unit
V_{DSS}	Drain-source voltage	V_{GS} = 0V	450	V
V_{GSS}	Gate-source voltage	V_{DS} = 0V	±30	V
I_D	Drain current		14	A
I_{DM}	Drain current (Pulsed)		42	A
I_{DA}	Avalanche current (Pulsed)	L = 200μH	14	A
P_D	Maximum power dissipation		40	W
T_{ch}	Channel temperature		–55 ~ +150	°C
T_{stg}	Storage temperature		–55 ~ +150	°C
V_{iso}	Isolation voltage	AC for 1minute, Terminal to case	2000	V
—	Weight	Typical value	2.0	g

Sep. 2001

ELECTRICAL CHARACTERISTICS (T_{ch} = 25°C)

Symbol	Parameter	Test conditions	Limits			Unit
			Min.	Typ.	Max.	
$V_{(BR)DSS}$	Drain-source breakdown voltage	I_D = 1mA, V_{GS} = 0V	450	—	—	V
$V_{(BR)GSS}$	Gate-source breakdown voltage	I_G = ±100μA, V_{DS} = 0V	±30	—	—	V
I_{GSS}	Gate-source leakage current	V_{GS} = ±25V, V_{DS} = 0V	—	—	±10	μA
I_{DSS}	Drain-source leakage current	V_{DS} = 450V, V_{GS} = 0V	—	—	1	mA
$V_{GS(th)}$	Gate-source threshold voltage	I_D = 1mA, V_{DS} = 10V	2.0	3.0	4.0	V
$r_{DS(ON)}$	Drain-source on-state resistance	I_D = 7A, V_{GS} = 10V	—	0.40	0.52	Ω
$V_{DS(ON)}$	Drain-source on-state voltage	I_D = 7A, V_{GS} = 10V	—	2.80	3.64	V
$\|y_{fs}\|$	Forward transfer admittance	I_D = 7A, V_{DS} = 10V	—	8.0	—	S
C_{iss}	Input capacitance	V_{DS} = 25V, V_{GS} = 0V, f = 1MHz	—	1250	—	pF
C_{oss}	Output capacitance		—	150	—	pF
C_{rss}	Reverse transfer capacitance		—	55	—	pF
$t_{d(on)}$	Turn-on delay time	V_{DD} = 200V, I_D = 7A, V_{GS} = 10V, R_{GEN} = R_{GS} = 50Ω	—	25	—	ns
t_r	Rise time		—	45	—	ns
$t_{d(off)}$	Turn-off delay time		—	250	—	ns
t_f	Fall time		—	90	—	ns
V_{SD}	Source-drain voltage	I_S = 7A, V_{GS} = 0V	—	1.5	2.0	V
$R_{th(ch-c)}$	Thermal resistance	Channel to case	—	—	3.13	°C/W